

Referências

- [1] H. Z. Song, Y. Nakata, Y. Okada, T. Miyazawa, T. Ohshima, M. Takatsu, M. Kawabe e N. Yokoyama, *Physica E* **21**, 625 (2004).
- [2] A. Hirai e K. M. Itoh, *Physica E* **23**, 248 (2004).
- [3] C. K. Hyon, S. C. Choi, S. -H. Song, S. W. Hwang, M. H. Son, D. Ahn, Y. J. Park e E. K. Kim, *Appl. Phys. Lett.* **77**, 2607 (2000).
- [4] “Fabricação de nanoestruturas semicondutoras em defeitos produzidos por microscopia de força atômica”, Tese de Doutorado, Departamento de Física – PUC-Rio, Henrique Duarte da Fonseca-Filho (2008).
- [5] H. D. Fonseca-Filho, R. Prioli, M. P. Pires, A. S. Lopes, P. L. Souza e F. A. Ponce, *Appl. Phys. Lett.* **90**, 013117 (2007).
- [6] H. D. Fonseca-Filho, R. Prioli, M. P. Pires, A. S. Lopes, P. L. Souza e F. A. Ponce, *Appl. Phys. A* **89**, 945 (2007).
- [7] C. R. Taylor, E. A. Stach, G. Salamo e A. P. Malshe, *Appl. Phys. Lett.* **87**, 073108 (2005).
- [8] C. Taylor, E. Marega, E. A. Stach, G. Salamo, L. Hussey, M. Munoz e A. Malshe, *Nanotechnology* **19**, 015301 (2008).
- [9] C. M. Almeida e R. Prioli, *J. Mater. Sci.* **43**, 5998 (2008).
- [10] C. M. Almeida, R. Prioli e F. A. Ponce, *J. Appl. Phys.* **104**, 113509 (2008).
- [11] C. M. Almeida e R. Prioli, “*Effect of the nanoindenter tip geometry on the mechanical deformation of indium phosphide*”, a ser submetido ao *J. Appl. Phys.*
- [12] C. M. Almeida, R. Prioli e F. A. Ponce, “*The influence of applied force, keeping the strain rate constant, on the nanomechanical properties of InP*”, trabalho em fase de elaboração.
- [13] William D. Callister, Jr., “*Ciência e Engenharia de Materiais Uma Introdução*”, Livros Técnicos e Científicos Editora S.A. (2008).
- [14] Peter Y. Yu e Manuel Cardona, “*Fundamentals of semiconductors: Physics and Materials Properties*”, Springer-Verlag 3th edition (2005).
- [15] <http://www.inpactsemicon.com>
- [16] “*Physical properties of Indium Phosphide*” Ioffe Physical Technical Institute, <http://www.ioffe.ru/SVA/NSM/Semicond/InP/index.html>
- [17] J. E. Bradby, J. S. Williams, J. Wong-Leung, S. O. Kucheyev, M. V. Swain e P. Monroe, *Phil. Mag. A* **82**, 1931 (2002).

- [18] D Hull e D. J. Bacon, “*Introduction to dislocation*”, Butterworth-Heinemann 4th edition (2001).
- [19] Q. Ren, B. Joós e M. S. Duesbery, Phys. Rev. B **52**, 13223 (1995).
- [20] A. George e J. Rabier, Revue Phys. Appl. **22**, 941 (1987).
- [21] J. F. Justo, A. Antonelli e A. Fazzio, Physica B **302-303**, 398 (2001).
- [22] P. D. Warren, P. Pirouz e S. G. Roberts, Phil. Mag. A **50**, L23 (1984).
- [23] M. S. Abrahams, J. Blanc e C. J. Buiocchi, Appl. Phys. Lett. **21**, 185 (1972).
- [24] D. Brasen, J. Mater. Sci. **11**, 791 (1976).
- [25] D.Y. Watts e A.F.W. Willoughby, J. Appl. Phys. **56**, 1869 (1984).
- [26] I. Yonenaga e K. Sumino, Appl. Phys. Lett. **58**, 48 (1991).
- [27] I. Yonenaga e K. Sumino, J. Appl. Phys. **74**, 917 (1993).
- [28] J. Rabier e P. Boivin, Phil. Mag. A **61**, 673 (1990).
- [29] Yu. S. Boyarskaya, D. Z. Grabko, M. I. Medinskaya e N. A. Palistrant, Semiconductors **31**, 139 (1997).
- [30] E. Le Bourhis, G. Patriarche, J.P.Riviere e A. Zozime, Phys. Stat. Solid (a) **161**, 415 (1997).
- [31] G. Patriarche e E. Le Bourhis, J. Mater. Sci. **36**, 1343 (2001).
- [32] E. Le Bourhis, J. Mater. Sci Lett. **19**, 167 (2000).
- [33] D. Grabco, N. Palistrant e E. Rusu, Mater. Sci. Eng. **B83**, 13 (2001).
- [34] E. Le Bourhis e G. Patriarche, Prog. Cryst. Growth Charact. **47**, 1 (2003).
- [35] J. E. Bradby, J. S. Williams, J. Wong-Leung, M. V. Swain e P. Munroe, Appl. Phys. Lett. **78**, 3235 (2001).
- [36] J. E. Bradby, J. S. Williams e M. V. Swain, J. Mater. Res. **19**, 380 (2004).
- [37] K. Wasmer, M. Parlinska-Wojtan, R. Gassilloud, C. Pouvreau, J. Tharian e J. Micher, Appl. Phys. Lett. **90**, 031902 (2007).
- [38] J. Yan, J. Tamaki, H. Zhao e T. Kuriyagawa, J. Micromech. Microeng. **18**, 105018 (2008).
- [39] James D. Dana “*Manual de Mineralogia*”, Livros Técnicos e Científicos Editora S.A. (1975).
- [40] S. Biwa e B. Storakers, J. Mech. Phys. Solids **43**, 1303 (1995).
- [41] W. C. Oliver, G. M. Pharr, J. Mater. Res. **7**, 1564 (1992)
- [42] Technical Note: “*Measuring the Radius of Curvature of a Probe Tip*”, Hysitron Inc.
http://www.hysitron.com/page_attachments/0000/0471/Measuring_the_Radius_of_Curvature_of_a_Probe_Tip.pdf
- [43] J. E. Lennard-Jones, Proc. Physical Society **43**, 31(1931).
- [44] E. Meyer, H. J. Hug e R. Bennewitz, "Scanning Probe Microscopy: The Lab on a Tip", Springer-Verlag (2004).
- [45] J. S. Villarrubia, J. Res. Natl. Inst. Stand. Technol. **102**, 425 (1997).

- [46] Swiss Center for Electronics and Microtechnology, AFM tip tester.
<http://www.csem.ch/fs/nanotech.htm>, CSEM, Switzerland.
- [47] <http://www.mathworks.com/products/matlab/>
- [48] www.ni.com/labview/
- [49] B. Bushan e V. N. Koinkar, Appl Phys Lett **64**, 1653 (1994).
- [50] R. Garcia e R. Perez, Surf Sci Rep **47**, 197 (2002).
- [51] B. Cretin e P. Vairac, Appl. Phys. A **66**, S235 (1998).
- [52] K. Tai, M. Dao, S. Suresh, A. Palazoglu e C. Ortiz, Nature Mater. **6**, 454 (2007).
- [53] M. R. Vanlandingham, S. H. McKnight, G. R. Palmese, J. R. Elings, X. Huang, T. A. Bogetti, R. F. Eduljee e J. W. Gillespie, J. of Adhesion **64**, 31(1997)
- [54] Fred W Billmeyer, “*Textbook of polymer science*”, Wiley-Interscience, New York 3rd edition (1984).
- [55] J. G. Swadener, E. P. George e G. M. Pharr, J. Mech. Phys. Solids **50**, 681 (2002).
- [56] C.E. Foerster, J.H. Stankiewicz, F.C. Serbena, C.M. Lepienski e F.C. Zawislak, Nucl. Instr. and Meth. in Phys. Res. B **257**, 510 (2007).
- [57] J. Song, J. F. L. Duval, M.A. Cohen Stuart, H. Hillborg, U. Gunst, H. F. Arlinghaus e G. J. Vancso, Langmuir **23**, 5430 (2007).
- [58] J. S. Field e M. V. Swain, J. Mater. Res. **8**, 297 (1993).
- [59] G. Hollinger, E. Bergignat, J. Joseph e Y. Robach, J. Vac. Sci. Technol. A **3**, 2082 (1985).
- [60] N. Shibata e H. Ikoma, Jpn. J. Appl. Phys. **31**, 3976 (1992).
- [61] M. Losurdo, P. Capezzuto e G. Bruno, J. Vac. Sci. Technol. B **14**, 691 (1996).
- [62] Y. Sun, Z. Liu, F. Machuca, P. Pianetta e W. E. Spicer, J. Appl. Phys. **97**, 124902 (2005).
- [63] J. N. Israelachvili, “*Intermolecular and Surface Forces*” (Academic Press, London, 1992), p. 327.
- [64] D. Kikuchi e S. Adachi, Mat. Sci. and Eng. B **76**, 133 (2000).
- [65] <http://www.axt.com/>
- [66] S. E. Grillo, M. Ducarroir, M. Nadal, E. Tournié e J-P. Faurie, J. Phys. D: Appl. Phys. **36**, L5 (2003).
- [67] M. W. Pruessner, T. T. King, D. P. Kelly, R. Grover, L. C. Calhoun e R. Ghodssi, Sensor and Actuators A **105**, 190 (2003).
- [68] www.fei.com/
- [69] http://www.tf.uni-kiel.de/matwis/amat/def_en/index.html